

Notice of References Cited	Application/Control No. 10/600,596		Applicant(s)/Patent Under Reexamination SHIBATA ET AL.	
	Examiner Stanley J. Pruchnic, Jr.		Art Unit 2859	Page 1 of 3

U.S. PATENT DOCUMENTS

<input type="checkbox"/>		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-6,666,577 B2	12-2003	Shibata et al.	374/141
*	B	US-6,638,629 B2	10-2003	Johnson et al.	428/446
*	C	US-6,616,331 B2	09-2003	Shibata et al.	374/141
*	D	US-6,580,140 B1	06-2003	Ballantine et al.	257/467
*	E	US-6,114,765 A	09-2000	Fujii et al.	257/757
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11160166 A	06-1999	Japan	TANAKA, HIROYUKI	G01K 15/00
	O	JP 2000232142 A	08-2000	Japan	NANBU et al.	H01L 21/66
	P	JP 09320988 A	12-1997	Japan	FUJII et al.	H01L 21/28
	Q	JP 07294569 A	11-1995	Japan	HARADA et al.	G01R 27/02
	R	JP 03079057 A	04-1991	Japan	ONISHI, SHIGEO	H01L 21/66
	S	JP 07248264 A	09-1995	Japan	MCARTHUR et al.	G01K 07/16
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	ABSTRACTED-PUB-NO: JP 11160166A, DERWENT-ACC-NO:1999-408057, DERWENT-WEEK:200335 (2003).
	V	Partial English Translation of Laid Open Unexamined Application Publ. No. JP 11160166A, Patent Abstracts of Japan (1999).
	W	ABSTRACTED-PUB-NO: JP 2000232142 A, DERWENT-ACC-NO:2001-083756, DERWENT-WEEK:200370 (2003).
	X	Patent Abstracts of Japan, JP 09320988 A, "SEMICONDUCTOR DEVICE AND ITS MANUFACTURE," (December 12, 1997).

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/600,596	Applicant(s)/Patent Under Reexamination SHIBATA ET AL.	
	Examiner Stanley J. Pruchnic, Jr.	Art Unit 2859	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U2	Partial English Translation of Laid Open Unexamined Application Publ. No. JP 09320988 A. Patent Abstracts of Japan (1997).
	V2	ABSTRACTED-PUB-NO: JP 07294569A, DERWENT-ACC-NO: 1996-023804, DERWENT-WEEK: 199603 (1996).
50P	W2	<i>Patent Abstracts of Japan, (APRIL 1991)</i> ABSTRACTED-PUB-NO: JP 03079057A, DERWENT-ACC-NO: 1991-143736, DERWENT-WEEK: 199120 (1991).
	X2	Patent Abstracts of Japan, JP 07248264 A, "TEMPERATURE MEASURING METHOD USING ION IMPLANTED WAFER," (September 26, 1995).

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/600,596	Applicant(s)/Patent Under Reexamination SHIBATA ET AL.	
	Examiner Stanley J. Pruchnic, Jr.	Art Unit 2859	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U 3	Notice of Reasons of Rejection, JPO Patent Application No. 2001-296288 for patent, English Translation (3 pages) December 2, 2003.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.